

Defect and Microstructure Analysis by Diffraction

ROBERT L. SNYDER

*Department of Materials Science and Engineering,
The Ohio State University,
Columbus, Ohio, USA*

JAROSLAV FIALA

*Department of Metallurgy, Central Research Institute Skoda,
Czech Republic*

and

HANS J. BUNGE

*Department of Physical Metallurgy,
Technical University of Clausthal, Germany*

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